

N-channel 600 V, 0.550 Ω typ., 7.5 A MDmesh™ M2 EP Power MOSFET in a DPAK package

Datasheet - production data

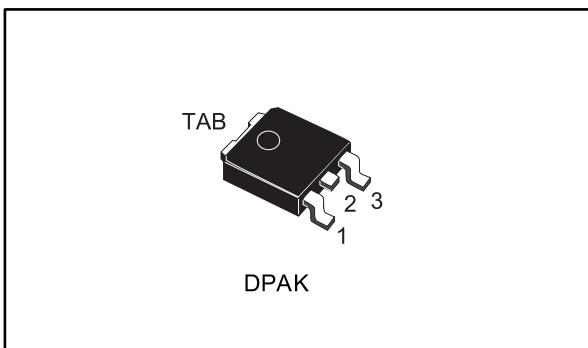
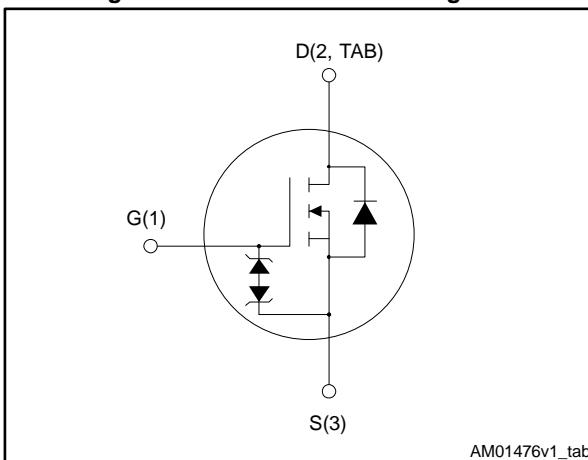


Figure 1: Internal schematic diagram



Features

| Order code | V_{DS} | $R_{DS(on)}$ max. | I_D |
|---------------|----------|-------------------|-------|
| STD11N60M2-EP | 600 V | 0.595 Ω | 7.5 A |

- Extremely low gate charge
- Excellent output capacitance (C_{OSS}) profile
- Very low turn-off switching losses
- 100% avalanche tested
- Zener-protected

Applications

- Switching applications

Description

This device is an N-channel Power MOSFET developed using MDmesh™ M2 EP enhanced performance technology. Thanks to its strip layout and an improved vertical structure, the device exhibits low on-resistance, optimized switching characteristics with very low turn-off switching losses, rendering it suitable for the most demanding very high frequency converters.

Table 1: Device summary

| Order code | Marking | Package | Packaging |
|---------------|-----------|---------|---------------|
| STD11N60M2-EP | 11N60M2EP | DPAK | Tape and reel |

Contents

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1 Electrical ratings

Table 2: Absolute maximum ratings

| Symbol | Parameter | Value | Unit |
|----------------|---|-------------|------------------|
| V_{GS} | Gate-source voltage | ± 25 | V |
| I_D | Drain current (continuous) at $T_C = 25^\circ\text{C}$ | 7.5 | A |
| I_D | Drain current (continuous) at $T_C = 100^\circ\text{C}$ | 4.7 | A |
| $I_{DM}^{(1)}$ | Drain current (pulsed) | 30 | A |
| P_{TOT} | Total dissipation at $T_C = 25^\circ\text{C}$ | 85 | W |
| $dv/dt^{(2)}$ | Peak diode recovery voltage slope | 15 | V/ns |
| $dv/dt^{(3)}$ | MOSFET dv/dt ruggedness | 50 | V/ns |
| T_{stg} | Storage temperature range | - 55 to 150 | $^\circ\text{C}$ |
| T_j | Operating junction temperature range | | |

Notes:

(1) Pulse width limited by safe operating area.

(2) $I_{SD} \leq 7.5$ A, $di/dt \leq 400$ A/ μs ; V_{DS} peak < $V_{(BR)DSS}$, $V_{DD} = 400$ V.(3) $V_{DS} \leq 480$ V**Table 3: Thermal data**

| Symbol | Parameter | Value | Unit |
|---------------------|--------------------------------------|-------|---------------------------|
| $R_{thj-case}$ | Thermal resistance junction-case max | 1.47 | $^\circ\text{C}/\text{W}$ |
| $R_{thj-pcb}^{(1)}$ | Thermal resistance junction-pcb max | 50 | $^\circ\text{C}/\text{W}$ |

Notes:(1) When mounted on FR-4 board of 1 inch², 2 oz Cu**Table 4: Avalanche characteristics**

| Symbol | Parameter | Value | Unit |
|----------|--|-------|------|
| I_{AR} | Avalanche current, repetitive or not repetitive (pulse width limited by T_{jmax}) | 2.4 | A |
| E_{AS} | Single pulse avalanche energy (starting $T_j = 25^\circ\text{C}$, $I_D = I_{AR}$; $V_{DD} = 50$ V) | 115 | mJ |

2 Electrical characteristics

$T_C = 25^\circ\text{C}$ unless otherwise specified

Table 5: On/off states

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|-----------------------------|-----------------------------------|--|------|-------|----------|---------------|
| $V_{(\text{BR})\text{DSS}}$ | Drain-source breakdown voltage | $V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$ | 600 | | | V |
| I_{DSS} | Zero gate voltage drain current | $V_{GS} = 0 \text{ V}, V_{DS} = 600 \text{ V}$ | | | 1 | μA |
| | | $V_{GS} = 0 \text{ V}, V_{DS} = 600 \text{ V}, T_C = 125^\circ\text{C}$ ⁽¹⁾ | | | 100 | μA |
| I_{GSS} | Gate-body leakage current | $V_{DS} = 0 \text{ V}, V_{GS} = \pm 25 \text{ V}$ | | | ± 10 | μA |
| $V_{GS(\text{th})}$ | Gate threshold voltage | $V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$ | 2 | 3 | 4 | V |
| $R_{DS(\text{on})}$ | Static drain-source on-resistance | $V_{GS} = 10 \text{ V}, I_D = 3.75 \text{ A}$ | | 0.550 | 0.595 | Ω |

Notes:

⁽¹⁾Defined by design, not subject to production test.

Table 6: Dynamic

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|--------------------------------------|-------------------------------|---|------|------|------|----------|
| C_{iss} | Input capacitance | $V_{DS} = 100 \text{ V}, f = 1 \text{ MHz}, V_{GS} = 0 \text{ V}$ | - | 390 | - | pF |
| C_{oss} | Output capacitance | | - | 22 | - | pF |
| C_{rss} | Reverse transfer capacitance | | - | 0.7 | - | pF |
| $C_{oss \text{ eq.}}$ ⁽¹⁾ | Equivalent output capacitance | $V_{DS} = 0 \text{ to } 480 \text{ V}, V_{GS} = 0 \text{ V}$ | - | 49 | - | pF |
| R_G | Intrinsic gate resistance | $f = 1 \text{ MHz}, I_D = 0 \text{ A}$ | - | 6.5 | - | Ω |
| Q_g | Total gate charge | $V_{DD} = 480 \text{ V}, I_D = 7.5 \text{ A}, V_{GS} = 10 \text{ V}$ (see Figure 16: "Test circuit for gate charge behavior") | - | 12.4 | - | nC |
| Q_{gs} | Gate-source charge | | - | 2.1 | - | nC |
| Q_{gd} | Gate-drain charge | | - | 7 | - | nC |

Notes:

⁽¹⁾ $C_{oss \text{ eq.}}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}

Table 7: Switching energy

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|--------------------|--|--|------|------|------|---------------|
| $E_{(\text{off})}$ | Turn-off energy (from 90% V_{GS} to 0% I_D) | $V_{DD} = 400 \text{ V}, I_D = 1 \text{ A}, R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}$ | - | 2.5 | - | μJ |
| | | $V_{DD} = 400 \text{ V}, I_D = 3 \text{ A}, R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}$ | - | 9 | - | μJ |

Table 8: Switching times

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|---------------|---------------------|--|-------------|-------------|-------------|-------------|
| $t_{d(on)}$ | Turn-on delay time | $V_{DD} = 300 \text{ V}$, $I_D = 3.75 \text{ A}$, $R_G = 4.7 \Omega$, $V_{GS} = 10 \text{ V}$ (see <i>Figure 15: "Test circuit for resistive load switching times"</i> and <i>Figure 20: "Switching time waveform"</i>) | - | 9 | - | ns |
| t_r | Rise time | | - | 5.5 | - | ns |
| $t_{d(off)}$ | Turn-off-delay time | | - | 26 | - | ns |
| t_f | Fall time | | - | 8 | - | ns |

Table 9: Source drain diode

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|-----------------|-------------------------------|---|-------------|-------------|-------------|---------------|
| I_{SD} | Source-drain current | | - | | 7.5 | A |
| $I_{SDM}^{(1)}$ | Source-drain current (pulsed) | | - | | 30 | A |
| $V_{SD}^{(2)}$ | Forward on voltage | $V_{GS} = 0 \text{ V}$, $I_{SD} = 7.5 \text{ A}$ | - | | 1.6 | V |
| t_{rr} | Reverse recovery time | $I_{SD} = 7.5 \text{ A}$, $dI/dt = 100 \text{ A}/\mu\text{s}$, $V_{DD} = 60 \text{ V}$ (see <i>Figure 17: "Test circuit for inductive load switching and diode recovery times"</i>) | - | 192 | | ns |
| Q_{rr} | Reverse recovery charge | | - | 1.32 | | μC |
| I_{RRM} | Reverse recovery current | | - | 13.8 | | A |
| t_{rr} | Reverse recovery time | | - | 262 | | ns |
| Q_{rr} | Reverse recovery charge | $I_{SD} = 7.5 \text{ A}$, $dI/dt = 100 \text{ A}/\mu\text{s}$, $V_{DD} = 60 \text{ V}$, $T_j = 150^\circ\text{C}$ (see <i>Figure 17: "Test circuit for inductive load switching and diode recovery times"</i>) | - | 1.74 | | μC |
| I_{RRM} | Reverse recovery current | | - | 13.3 | | A |

Notes:

(1)Pulse width is limited by safe operating area

(2)Pulsed: pulse duration = 300 μs , duty cycle 1.5%

2.2 Electrical characteristics (curves)

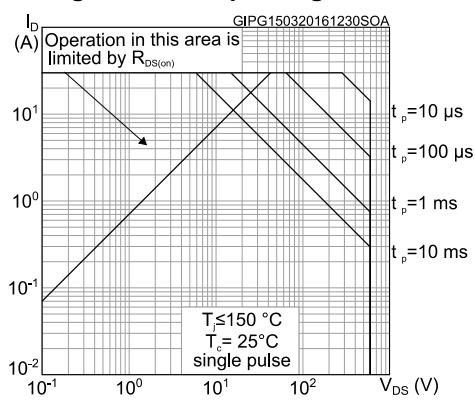
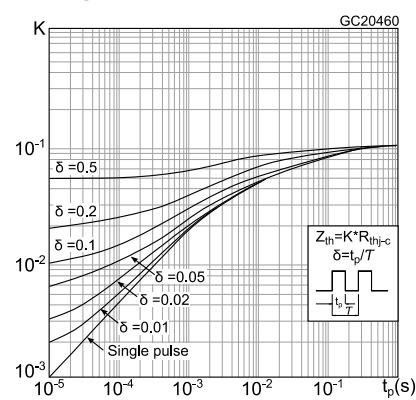
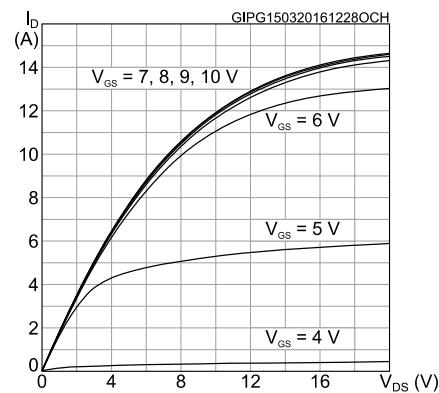
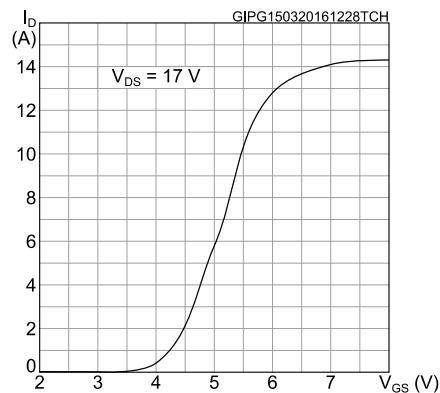
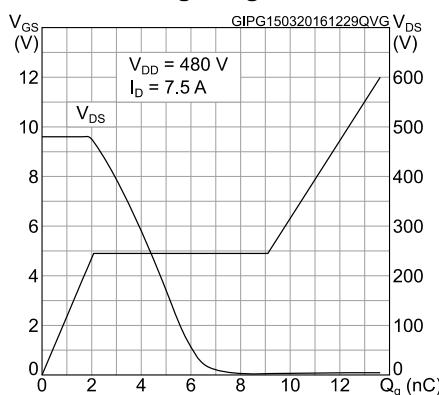
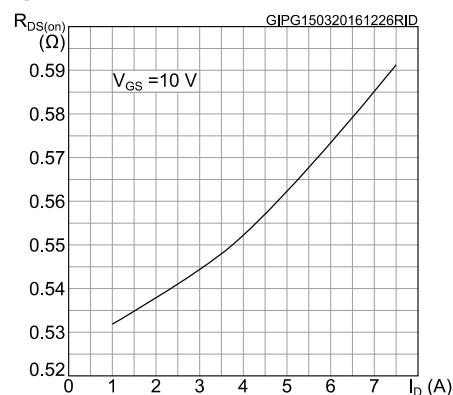
Figure 2: Safe operating area**Figure 3: Thermal impedance****Figure 4: Output characteristics****Figure 5: Transfer characteristics****Figure 6: Gate charge vs gate-source voltage****Figure 7: Static drain-source on-resistance**

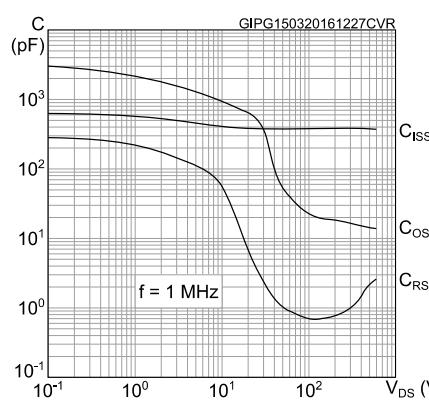
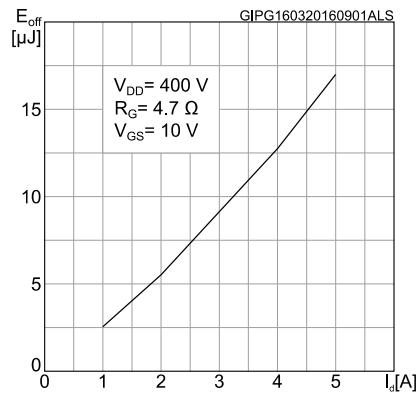
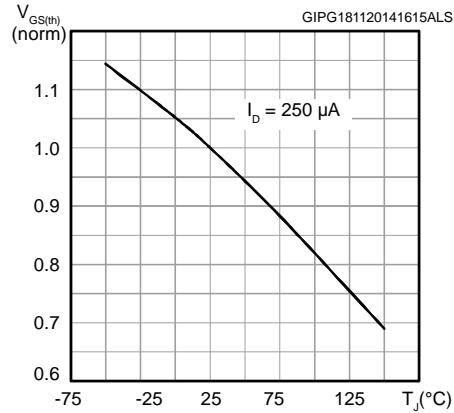
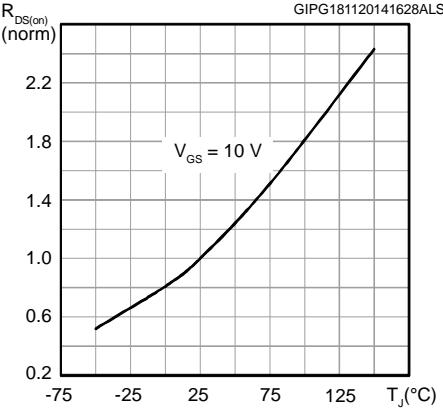
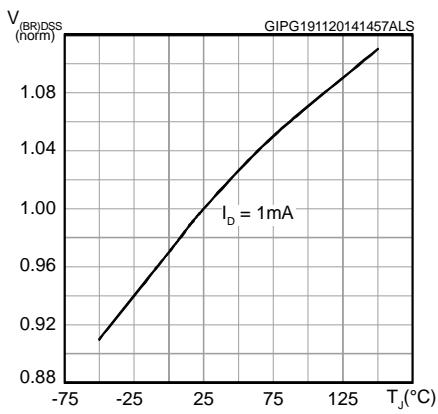
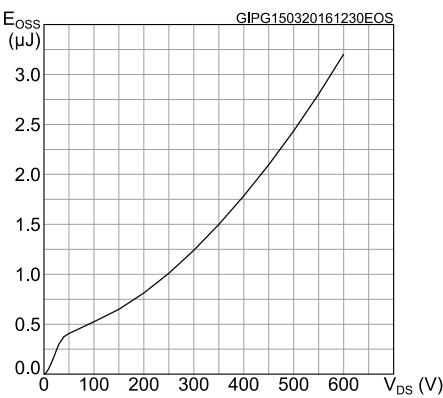
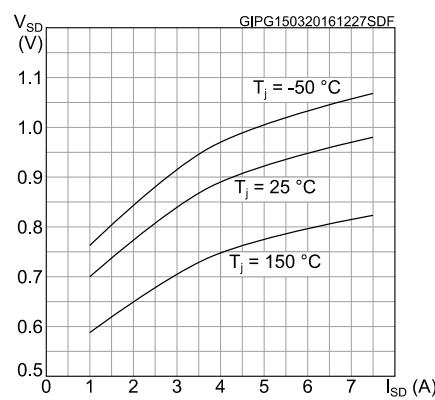
Figure 8: Capacitance variations**Figure 9: Turn-off switching energy vs drain current****Figure 10: Normalized gate threshold voltage vs temperature****Figure 11: Normalized on-resistance vs temperature****Figure 12: Normalized V_(BR)DSS vs temperature****Figure 13: Output capacitance stored energy**

Figure 14: Source-drain diode forward characteristics

3 Test circuits

Figure 15: Test circuit for resistive load switching times

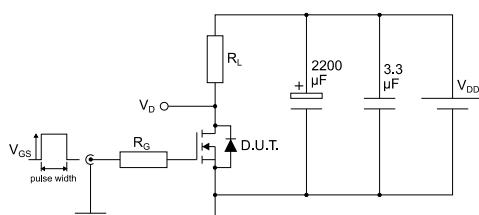


Figure 16: Test circuit for gate charge behavior

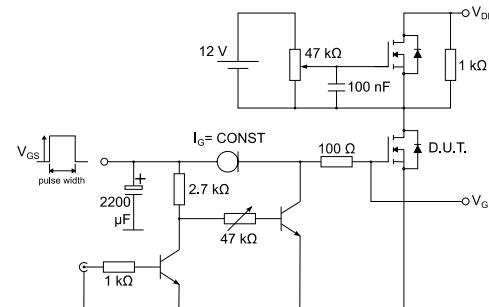


Figure 17: Test circuit for inductive load switching and diode recovery times

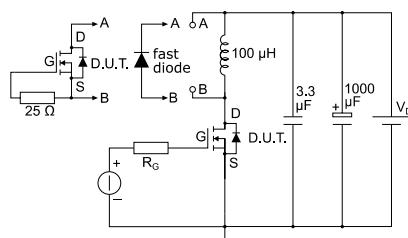


Figure 18: Unclamped inductive load test circuit

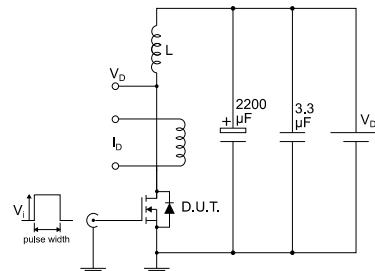


Figure 19: Unclamped inductive waveform

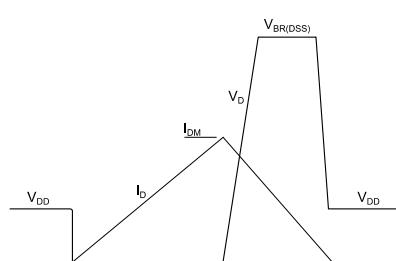
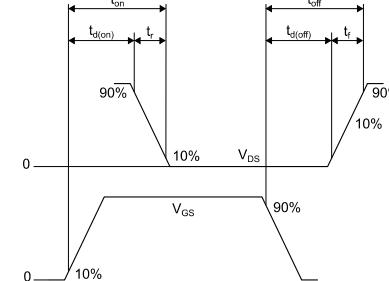


Figure 20: Switching time waveform

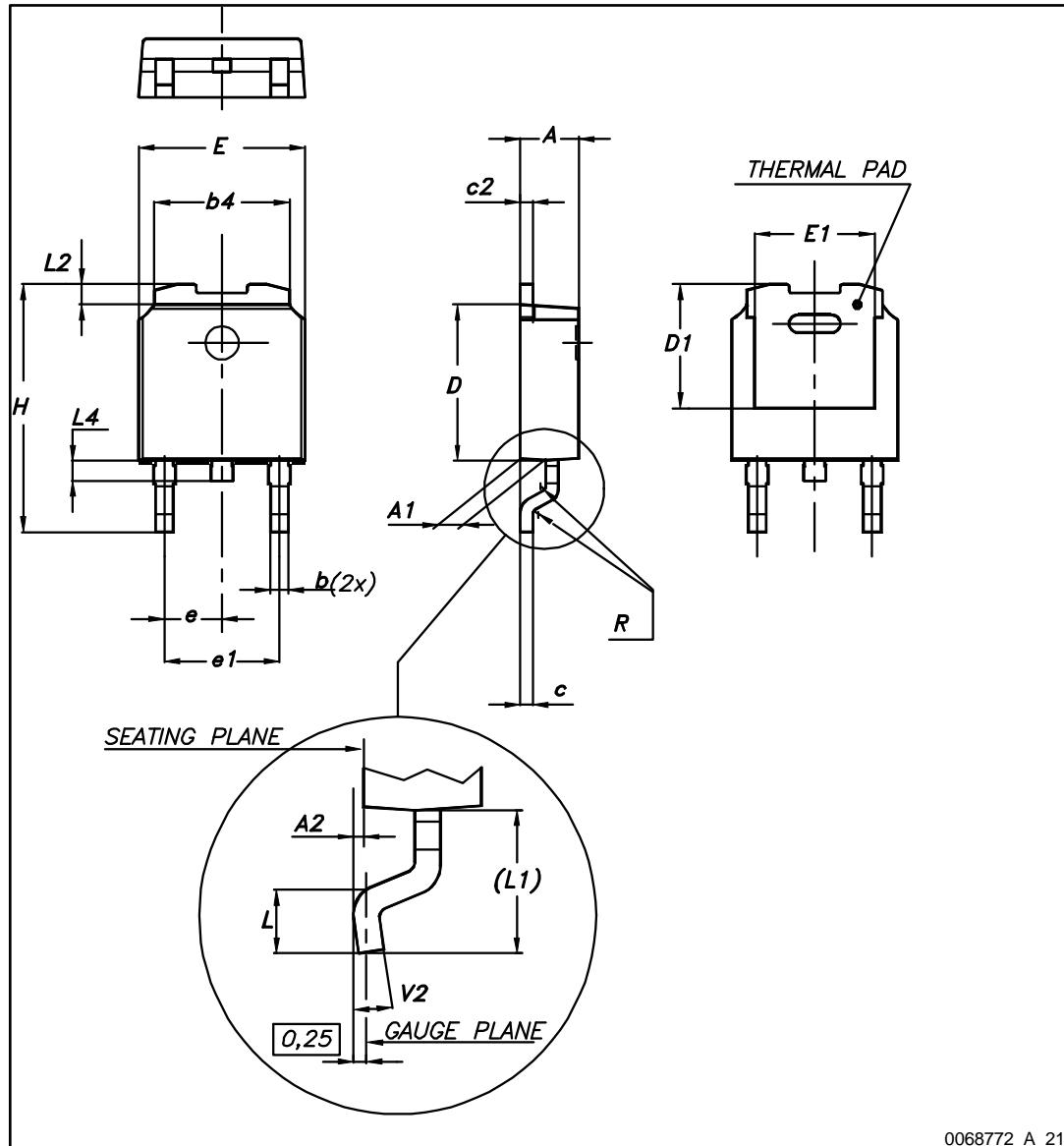


4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com.
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4.1 DPAK (TO-252) type A package information

Figure 21: DPAK (TO-252) type A package outline

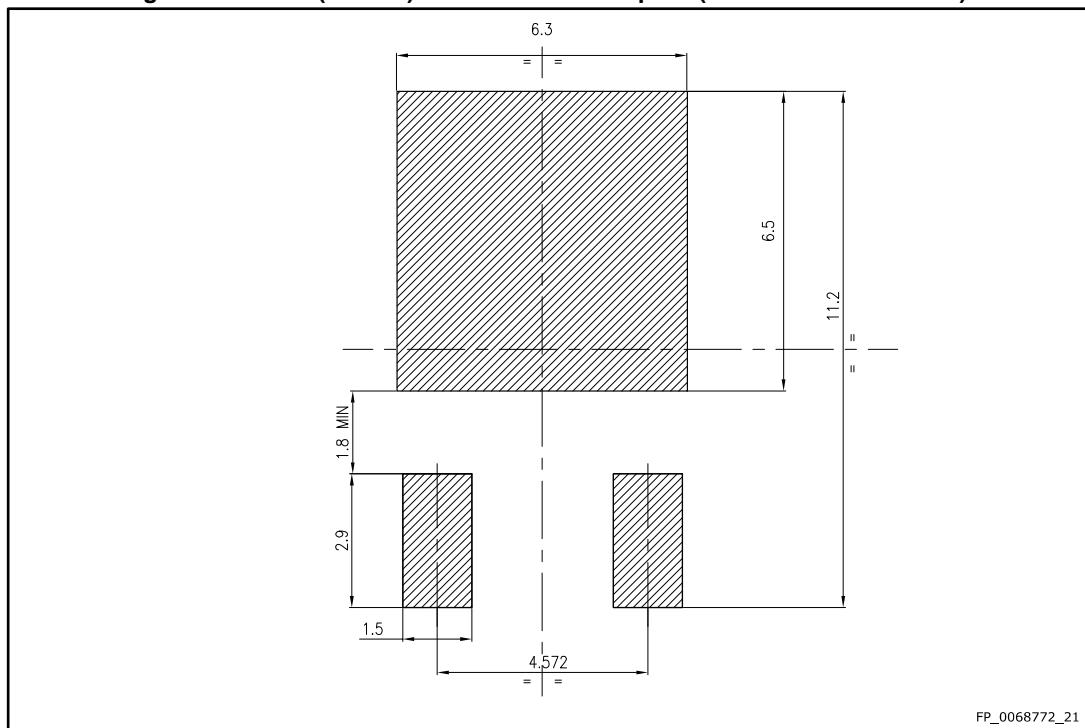


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Table 10: DPAK (TO-252) type A mechanical data

| Dim. | mm | | |
|------|------|------|-------|
| | Min. | Typ. | Max. |
| A | 2.20 | | 2.40 |
| A1 | 0.90 | | 1.10 |
| A2 | 0.03 | | 0.23 |
| b | 0.64 | | 0.90 |
| b4 | 5.20 | | 5.40 |
| c | 0.45 | | 0.60 |
| c2 | 0.48 | | 0.60 |
| D | 6.00 | | 6.20 |
| D1 | 4.95 | 5.10 | 5.25 |
| E | 6.40 | | 6.60 |
| E1 | 4.60 | 4.70 | 4.80 |
| e | 2.16 | 2.28 | 2.40 |
| e1 | 4.40 | | 4.60 |
| H | 9.35 | | 10.10 |
| L | 1.00 | | 1.50 |
| (L1) | 2.60 | 2.80 | 3.00 |
| L2 | 0.65 | 0.80 | 0.95 |
| L4 | 0.60 | | 1.00 |
| R | | 0.20 | |
| V2 | 0° | | 8° |

Figure 22: DPAK (TO-252) recommended footprint (dimensions are in mm)



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5 DPAK (TO-252) packing information

Figure 23: DPAK (TO-252) tape outline

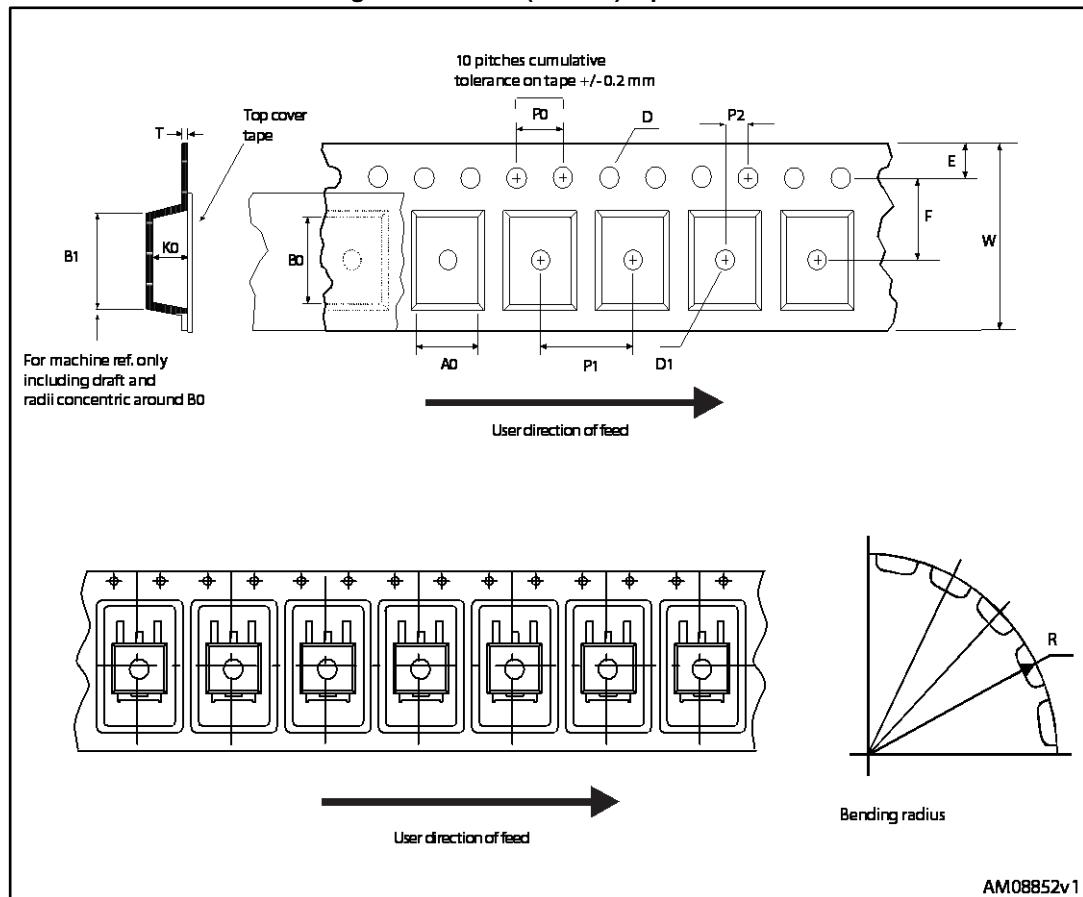


Figure 24: DPAK (TO-252) reel outline

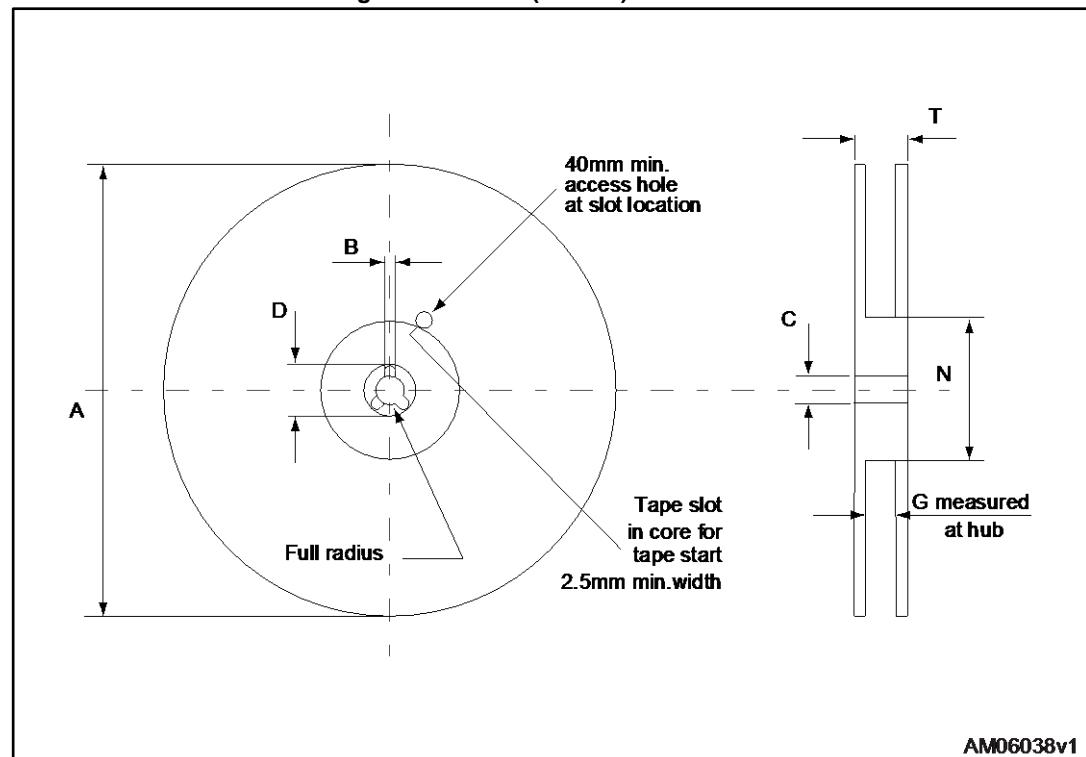


Table 11: DPAK (TO-252) tape and reel mechanical data

| Tape | | | Reel | | |
|------|------|------|-----------|------|------|
| Dim. | mm | | Dim. | mm | |
| | Min. | Max. | | Min. | Max. |
| A0 | 6.8 | 7 | A | | 330 |
| B0 | 10.4 | 10.6 | B | 1.5 | |
| B1 | | 12.1 | C | 12.8 | 13.2 |
| D | 1.5 | 1.6 | D | 20.2 | |
| D1 | 1.5 | | G | 16.4 | 18.4 |
| E | 1.65 | 1.85 | N | 50 | |
| F | 7.4 | 7.6 | T | | 22.4 |
| K0 | 2.55 | 2.75 | | | |
| P0 | 3.9 | 4.1 | Base qty. | | 2500 |
| P1 | 7.9 | 8.1 | Bulk qty. | | 2500 |
| P2 | 1.9 | 2.1 | | | |
| R | 40 | | | | |
| T | 0.25 | 0.35 | | | |
| W | 15.7 | 16.3 | | | |

6 Revision history

Table 12: Document revision history

| Date | Revision | Changes |
|-------------|----------|----------------|
| 12-Apr-2016 | 1 | First release. |

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